

### 6A, 700V N-CHANNEL MOSFET

### DESCRIPTION

SVF6N70AD(F)(MJ) is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell<sup>™</sup> high-voltage planar VDMOS technology. The improved process and cell structure have been especially tailored to minimize on-state resistance, provide superior switching performance, and high avalanche breakdown resistance.

These devices are widely used in AC-DC power supplies, DC-DC converters and H-bridge PWM motor drivers.

#### **FEATURES**

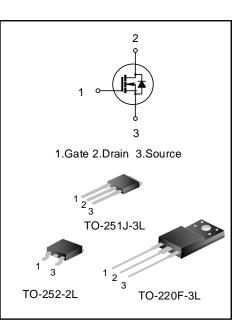
- 6A, 700V, R<sub>DS(on)(typ.)</sub>=1.6Ω@V<sub>GS</sub>=10V
- Low gate charge
- Low Crss
- Fast switching
- Improved dv/dt capability
- 100% avalanche tested
- Pb-free lead plating
- RoHS compliant

#### **KEY PERFORMANCE PARAMETERS**

Characteristics	Ratings	Unit
V <sub>DS</sub>	700	V
V <sub>GS(th)</sub>	2.0~4.0	V
R <sub>DS(on)</sub> , max.	1.8	Ω
I <sub>D.pulse</sub>	24	А
Q <sub>g.typ.</sub>	20	nC

#### **ORDERING INFORMATION**

Part No.	Package	Marking	Hazardous Substance Control	Packing Type
SVF6N70ADTR	TO-252-2L	6N70AD	Halogen free	Tape & Reel
SVF6N70AF	TO-220F-3L	SVF6N70AF	pb free	Tube
SVF6N70AMJ	TO-251J-3L	SVF6N70A	Halogen free	Tube





### ABSOLUTE MAXIMUM RATINGS (UNLESS OTHERWISE NOTED, TJ=25°C)

Ohanastanistiss		<b>T</b> 1 111	Ratings			Unit
Characteristics	Symbol Test conditions		Min.	Тур.	Typ. Max.	
Drain-source Voltage	V <sub>DS</sub>		700			V
Gate-source Voltage	V <sub>GS</sub>		-30		30	V
Drain Current	1	T <sub>C</sub> =25°C			6.0	A
Drain Current	ID	T <sub>C</sub> =100°C			3.8	A
Drain Current Pulsed (Note 1)	I <sub>DM</sub>	T <sub>C</sub> =25°C			24	А
Power Dissipation (TO-252-2L) (TO-251J-3L) (Note 2)	P <sub>D</sub>	T <sub>C</sub> =25°C			119	W
Power Dissipation (TO-220F-3L) (Note 2)	P <sub>D</sub>	T <sub>c</sub> =25°C			43	W
Single Pulsed Avalanche Energy	E <sub>AS</sub>	L=10mH, $V_{DD}$ =100V, $R_G$ =25 $\Omega$ , starting temperature $T_J$ =25°C			245	mJ
Single pulse avalanche current	I <sub>AS</sub>				6.6	А
Reverse Diode dv/dt	dv/dt	$V_{DS}$ =0~600V, $I_{SD}$ <= $I_S$ , $T_J$ =25°C			4.5	V/ns
MOS dv/dt Ruggedness	dv/dt	V <sub>DS</sub> =0~640V			50	V/ns
Operation Junction Temperature Range	TJ		-55		150	°C
Storage Temperature Range	T <sub>stg</sub>		-55		150	°C
Continuous Diode Forward Current	I <sub>S</sub>	T <sub>c</sub> =25°C, integral reverse P-N			6.0	А
Diode Pulse Current	I <sub>S</sub> ,pulse	junction diode in the MOSFET			24	A
Maximum Diode Commutation Speed	di/dt	V <sub>DS</sub> =0~400V, I <sub>SD</sub> <= I <sub>S</sub> , T <sub>J</sub> =25°C			250	A/µs

#### THERMAL CHARACTERISTICS

Table 1. TO-252-2L/TO-251J-3L (SVF6N70AD/MJ)

Characteristics	Sumbol	Symbol Test conditions		Ratings		
Gharacteristics	Symbol Test conditions	Test conditions	Min.	Тур.	Max.	Unit
Thermal Resistance,	Б				1.05	°C/W
Junction-case, Bottom	$R_{ extsf{ heta}JC}$				1.05	-C/VV
Thermal Resistance,	Б				62.0	°C/W
Junction-ambient	$R_{ extsf{ heta}JA}$				02.0	-C/VV
Soldoring Tomporature (SMD)	т	Reflow soldering: $10\pm1$ sec,			260	•••
Soldering Temperature (SMD)	$T_{sold}$	3times			200	°C
Soldering Temperature (in line)	Tsold	15 <sup>+2</sup> sec, 1time			260	°C



### Table 2. TO-220F-3L (SVF6N70AF)

Character	ristics	Symbol Test conditions		Ratings			Unit
Character	ristics Symbol Test conditions		Test conditions	Min. Typ. Max.			
Thermal	Resistance,	Rejc				2.91	°C/W
Junction-case, Bott	tom	КөJС				2.91	-0/00
Thermal	Resistance,	Б				62.5	°C/W
Junction-ambient		$R_{ extsf{ heta}JA}$				02.5	-0/00
Soldering Tempera	ature (in line)	Tsold	15 <sup>+2</sup> <sub>-0</sub> sec, 1time			260	°C



### ELECTRICAL CHARACTERISTICS (UNLESS OTHERWISE NOTED, TJ=25°C)

#### Static characteristics

Characteristics	Sumbol	Symbol Test conditions		Ratings			
Characteristics	Symbol	Test conditions	Min.	Тур.	Max.	Unit	
Drain-source Breakdown Voltage	$BV_{DSS}$	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA	700			V	
Drain aguras Lockago Current	1	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C			1.0	μA	
Drain-source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C		3.0		μA	
Gate-source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±30V, V <sub>DS</sub> =0V			±100	nA	
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{GS}=V_{DS}$ , $I_{D}=250\mu A$	2.0		4.0	V	
Static Drain-source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =3.0A		1.6	1.8	Ω	
Gate Resistance	R <sub>G</sub>	f=1MHz		3.9		Ω	

#### **Dynamic characteristics**

Characteristics	Symbol	Test conditions		Ratings		Unit
Characteristics			Min.	Тур.	Max.	Onit
Input Capacitance	C <sub>iss</sub>			711		
Output Capacitance	C <sub>oss</sub>	f=1MHz, V <sub>GS</sub> =0V, V <sub>DS</sub> =25V		79		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			7.2		
Turn-on Delay Time	t <sub>d(on)</sub>			14		
Turn-on Rise Time	tr	V <sub>DD</sub> =350V, V <sub>GS</sub> =10V, R <sub>G</sub> =25Ω, I <sub>D</sub> =6.0A		29		20
Turn-off Delay Time	t <sub>d(off)</sub>			49		ns
Turn-off Fall Time	t <sub>f</sub>	(Notes 3, 4)		31		
Total Gate Charge	Qg			20		
Gate-source Charge	Q <sub>gs</sub>	V <sub>DD</sub> =560V, V <sub>GS</sub> =10V, I <sub>D</sub> =6.0A		5.1		nC
Gate-drain Charge	Q <sub>gd</sub>	(Notes 3, 4)		8.7		
Gate-plateau Voltage	V <sub>plateau</sub>			6.2		V

#### **Reverse diode characteristics**

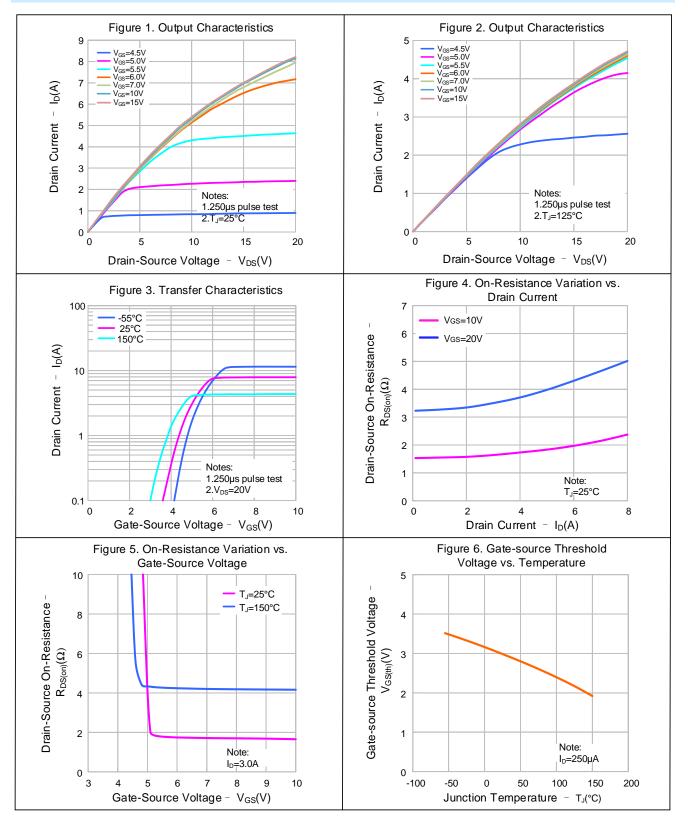
Characteristics	Symbol	Test conditions		Ratings		Unit
Gharacteristics	Symbol Test conditions		Min.	Тур.	Max.	Unit
Diode Forward Voltage	$V_{SD}$	I <sub>S</sub> =6.0A, V <sub>GS</sub> =0V			1.4	V
Reverse Recovery Time	Trr	I <sub>S</sub> =6.0A, V <sub>GS</sub> =0V,		458		ns
Reverse Recovery Charge	Qrr	dI <sub>F</sub> /dt=100A/µs		2.9		μC
Reverse Recovery Peak Current	I <sub>rrm</sub>	(Note 3)		14		А

#### Notes:

- 1. Pulse time 5µs;
- The dissipation power will change with temperature, derating above 25°C: 0.95W/°C(TO-252-2L)(TO-251J-3L)/0.34W/°C(TO-220F-3L)
- 3. Pulse Test: Pulse width  $\leq$ 300µs, Duty cycle $\leq$ 2%;
- 4. Essentially independent of operating temperature.

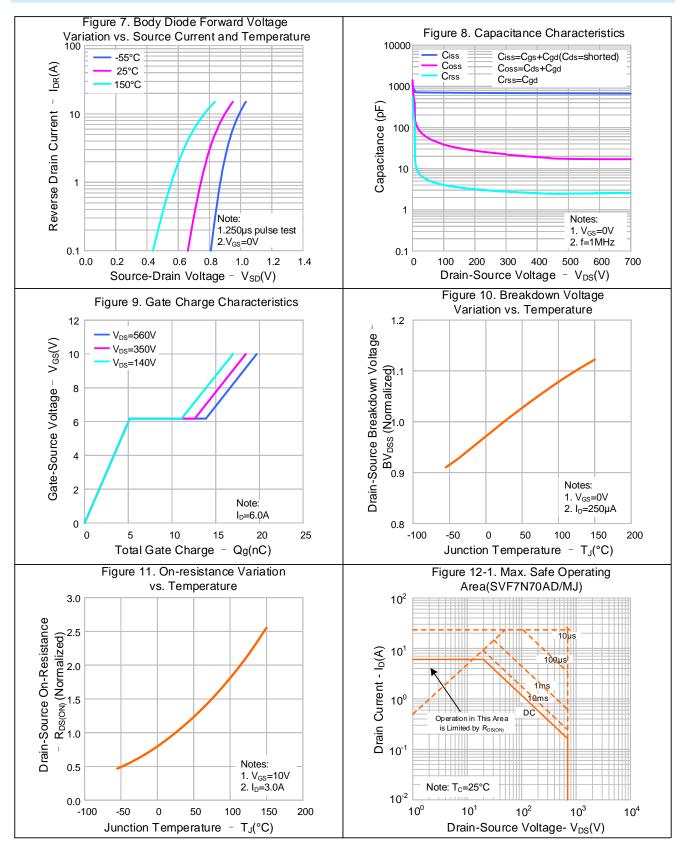


#### **TYPICAL CHARACTERISTICS**

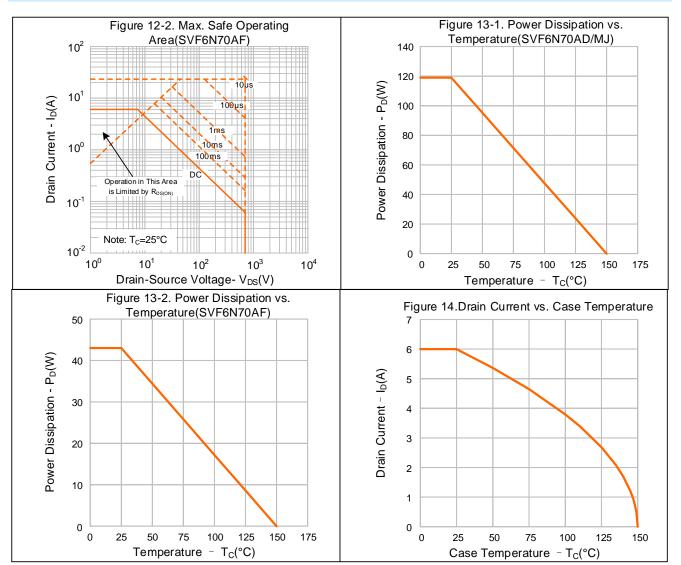




#### **TYPICAL CHARACTERISTICS (CONTINUED)**



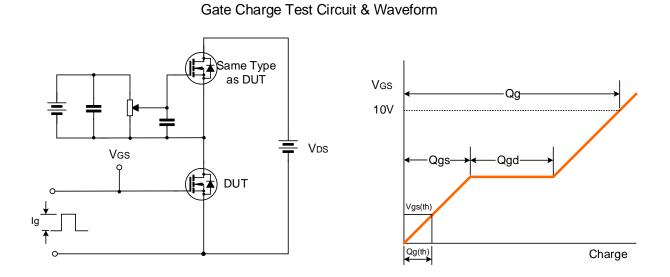




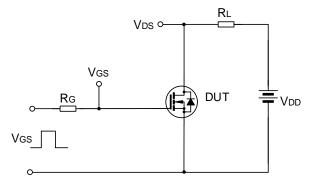
### **TYPICAL CHARACTERISTICS (CONTINUED)**

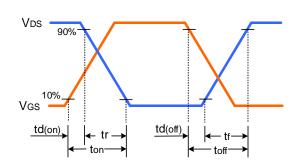


### **TYPICAL TEST CIRCUIT**

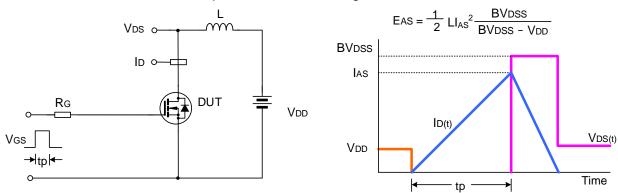


Resistive Switching Test Circuit & Waveform



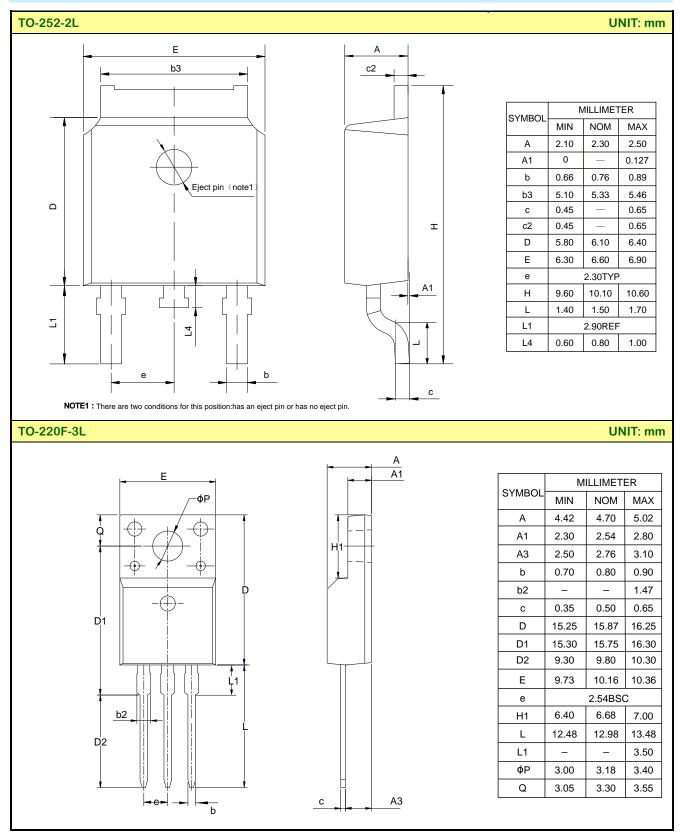


### Unclamped Inductive Switching Test Circuit & Waveform



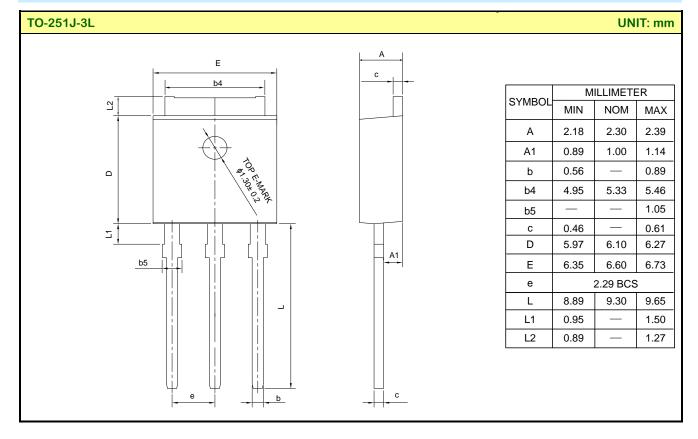


#### PACKAGE OUTLINE





#### PACKAGE OUTLINE (CONTINUED)





#### MOS DEVICES OPERATE NOTES:

Electrostatic charges may exist in many things. Please take following preventive measures to prevent effectively the MOS electric circuit as a result of the damage which is caused by discharge:

- The operator must put on wrist strap which should be earthed to against electrostatic.
- Equipment cases should be earthed.
- All tools used during assembly, including soldering tools and solder baths, must be earthed.
- MOS devices should be packed in antistatic/conductive containers for transportation.



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